

[METHOD AND APPARATUS FOR DETECTING X-RAYS]

Abstract of Disclosure

The present invention relates to a method of detecting X-rays for obtaining improved radiographic images including a step of orienting a semiconductor radiation detector whose height is greater than its thickness. The orienting step comprises a selection of an acute angle between a direction of incident radiation and a side of said detector having said height such that said incident radiation mainly hit the side of said radiation detector. The hit area excludes at least a section between at least one edge of said detector and at least an active sensor area and that substantially all of the energy of the radiation is dissipated within the detector.

Figures